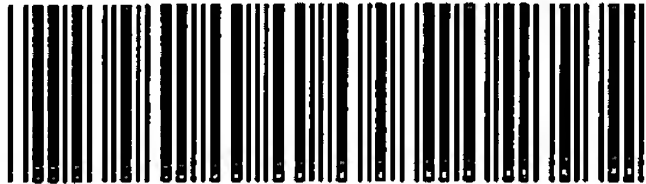


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/662,728	GARG ET AL.	
	Examiner	Art Unit	
	Mark D. Fearer	2109	

SEARCHED			
Class	Subclass	Date	Examiner
709	232	4/17/2007	MDF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	4/17/2007	MDF
consulted with Rafael Perez-Gutierrez	4/17/2007	MDF
garg.in. or kappes.in.	4/17/2007	MDF
AVAYA.as.	4/17/2007	MDF
@ad<"20030915" and ((random near3 early near3 (detect\$3 or discard\$3)) or ((back-pressure or (back near3 pressure)))	4/17/2007	MDF
@ad<"20030915" and (Pause near3 frame)	4/17/2007	MDF
@ad<"20030915" and (Pause near3 frame near3 procedure near3 IEEE near3 "802.3") or (back-pressure or (back near3 pressure)))	4/17/2007	MDF
"6650640" and (second)	4/17/2007	MDF